

### Electronic Supplementary Information (ESI)

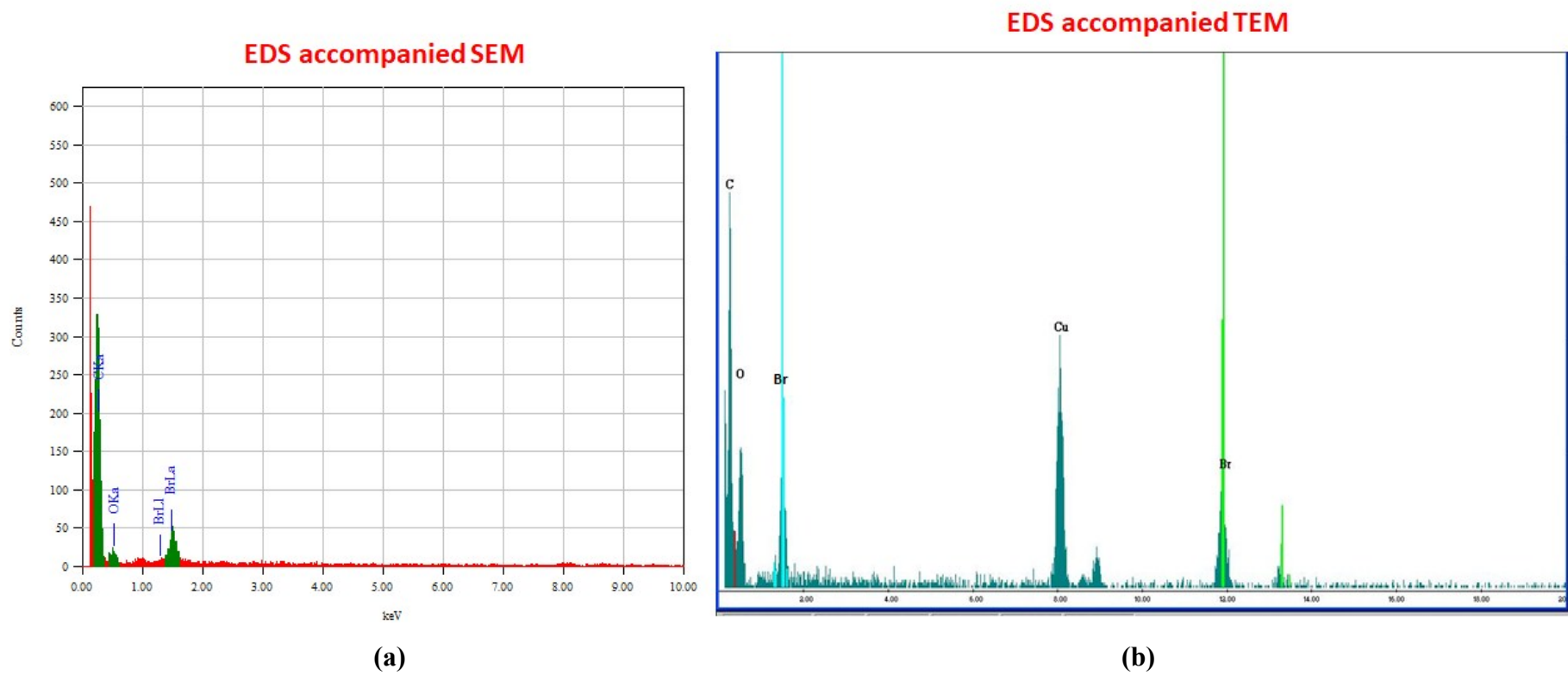
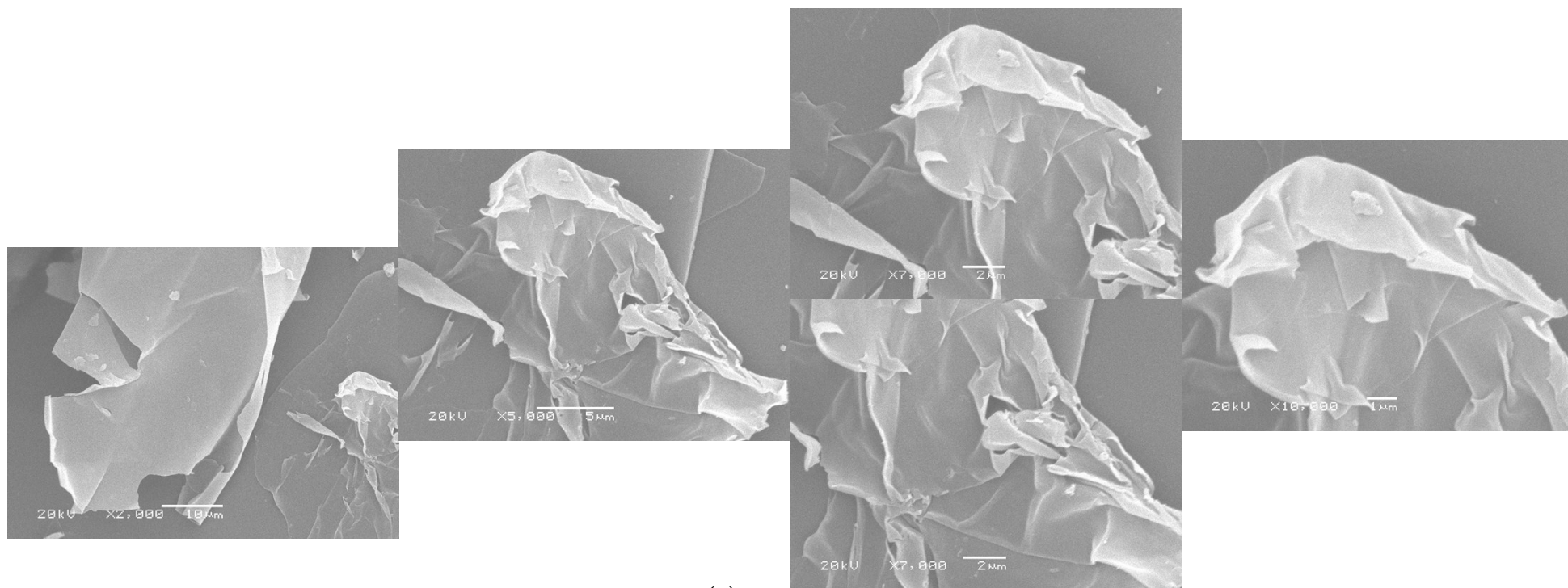
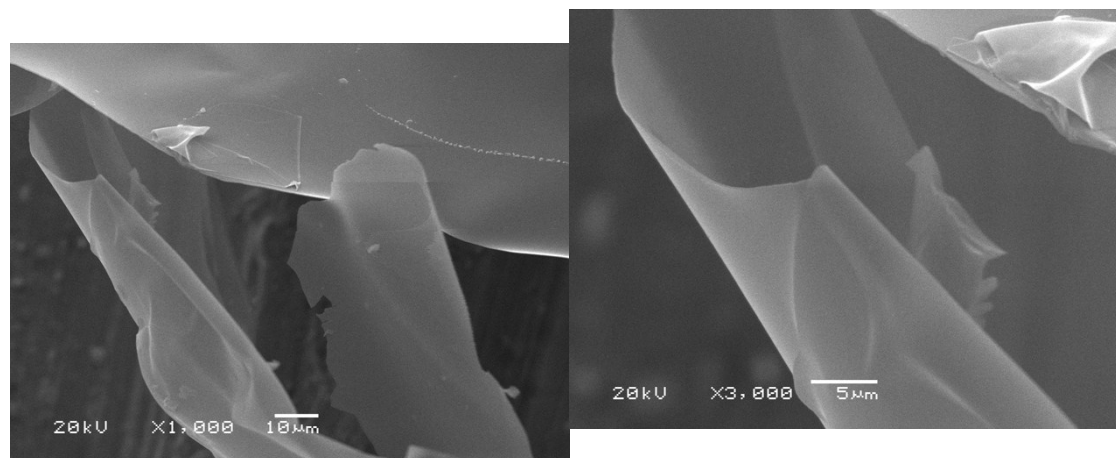


Fig. S1 EDS analysis of H-NGs270 accompanied (a) SEM and (b) TEM microscopy

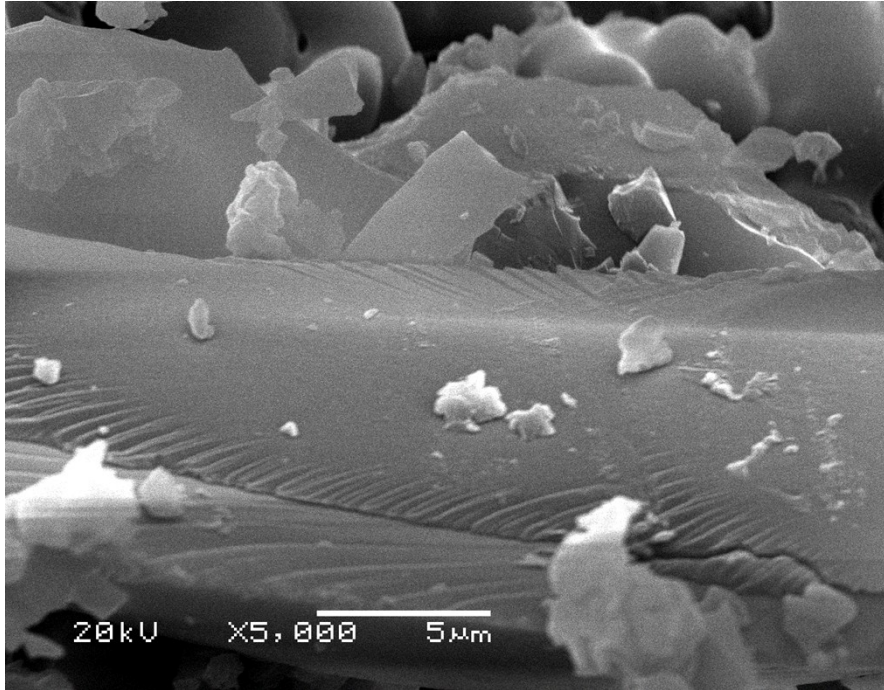


(a)

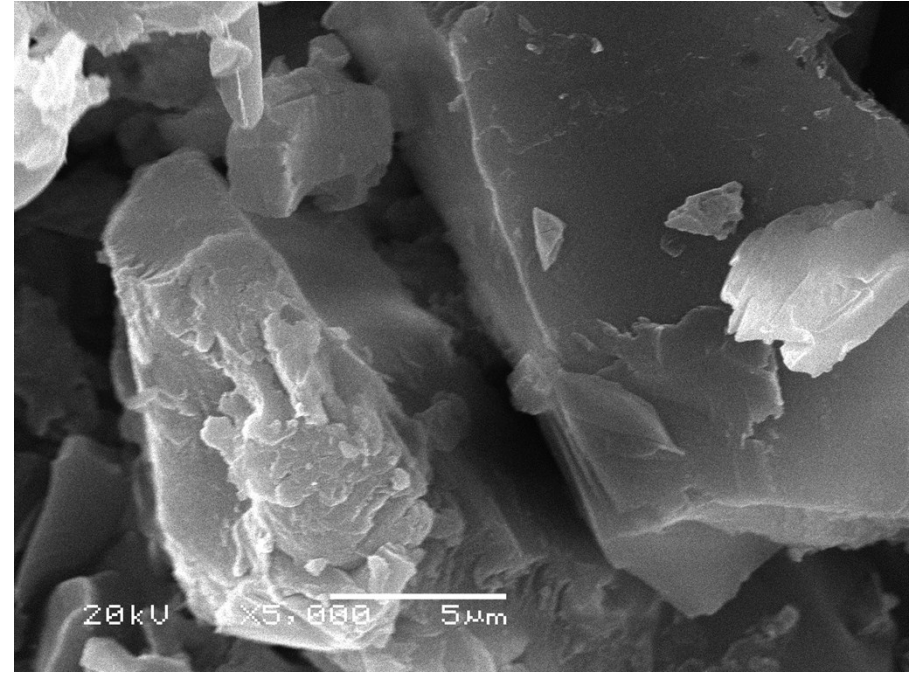


(b)

**Fig. S2 SEM imaging of H-NGs270 captured gradually from low to high magnifications at two different regions.  
(a) Region 1 and (b) Region 2**

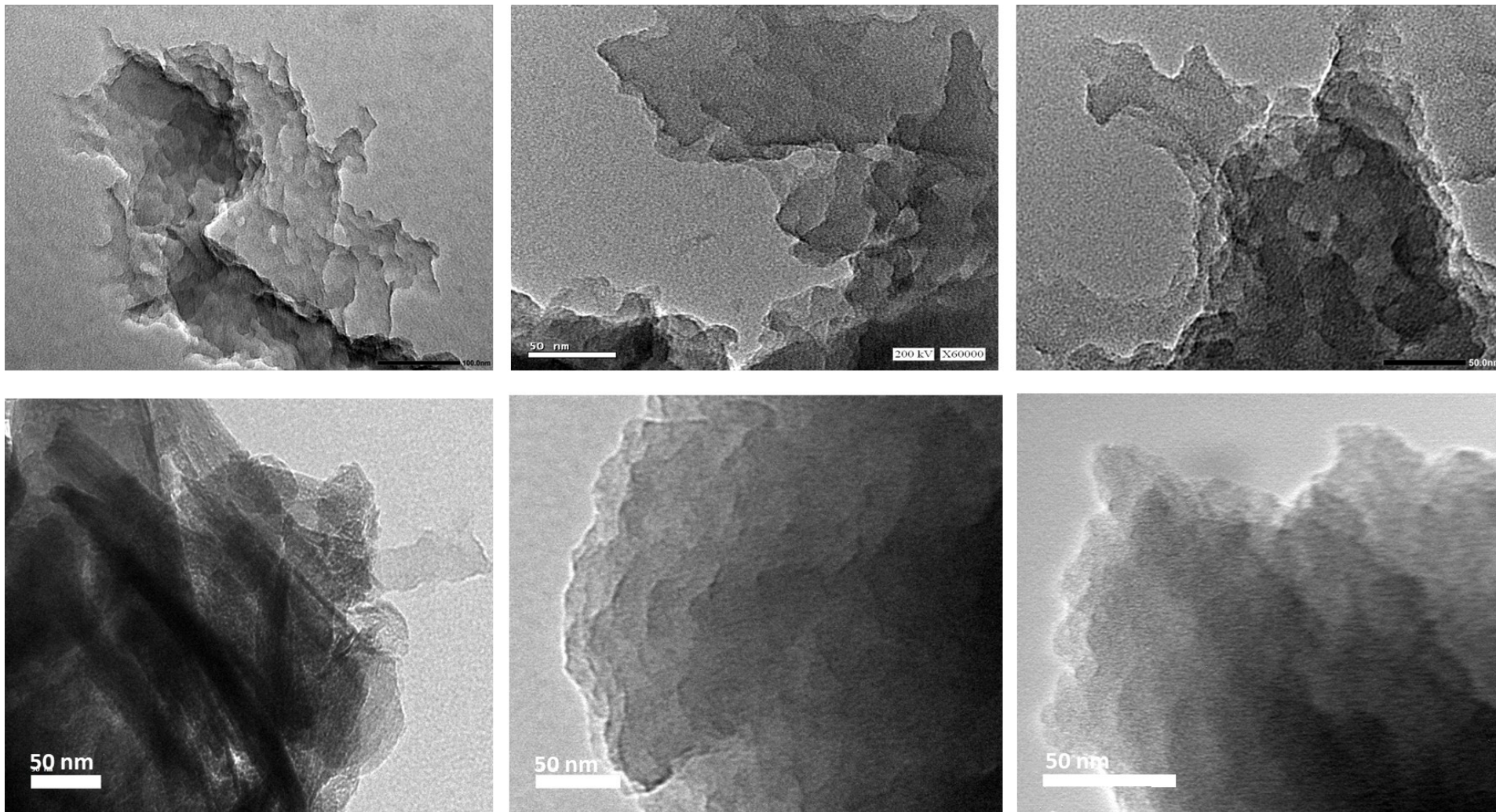


(a)

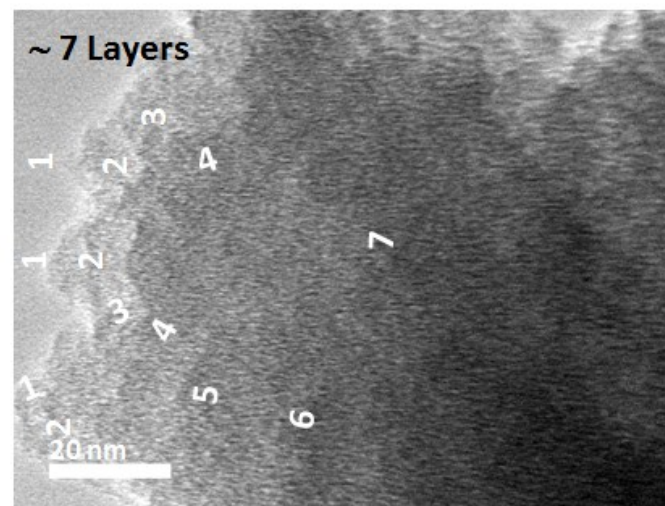
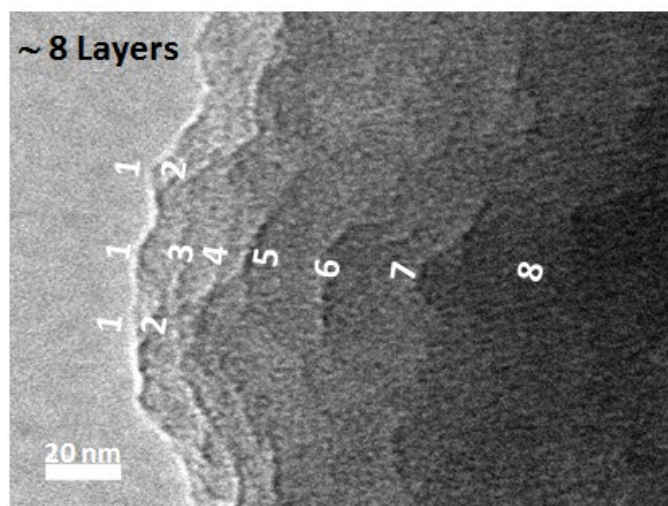
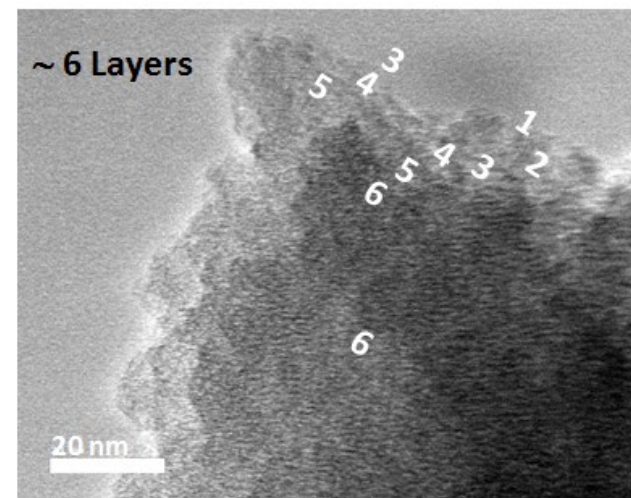
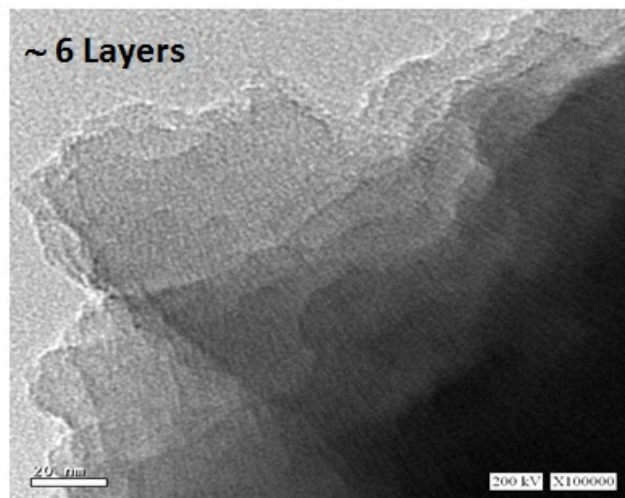
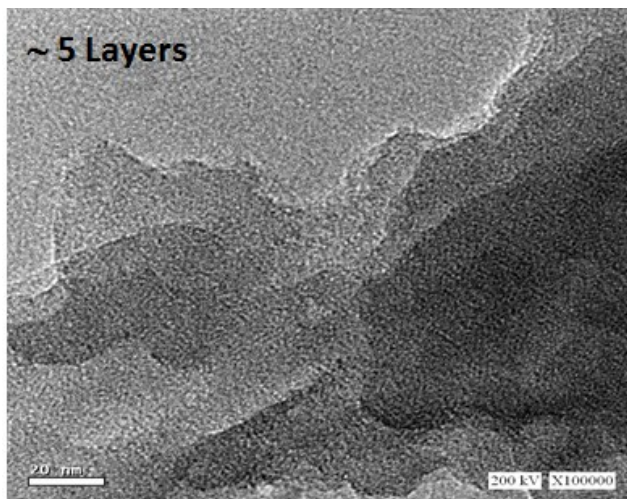


(b)

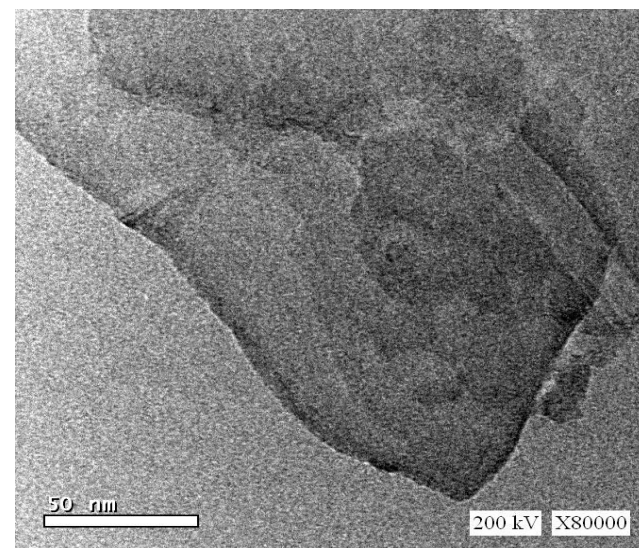
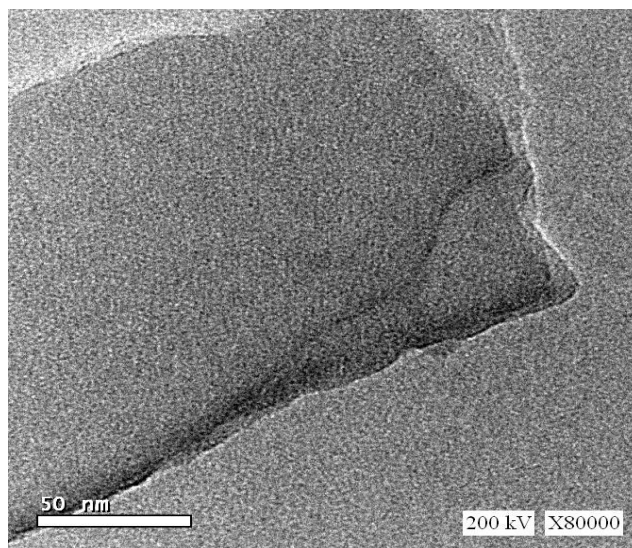
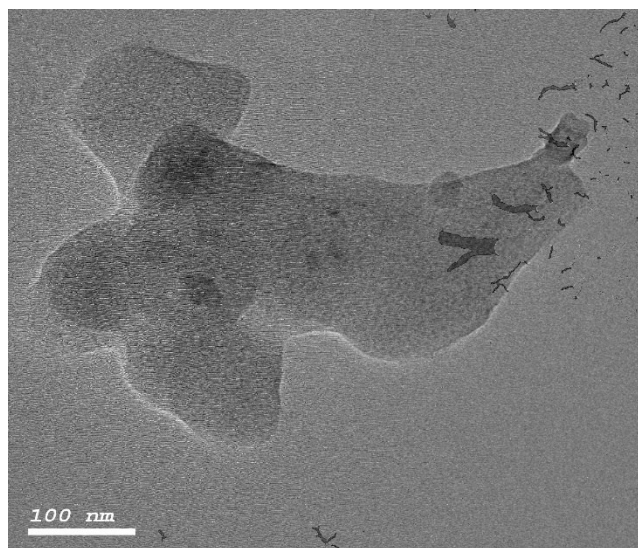
**Fig. S3 SEM micrographs of HTA-NG600 at two different regions. (a) Region 1 and (b) Region 2**



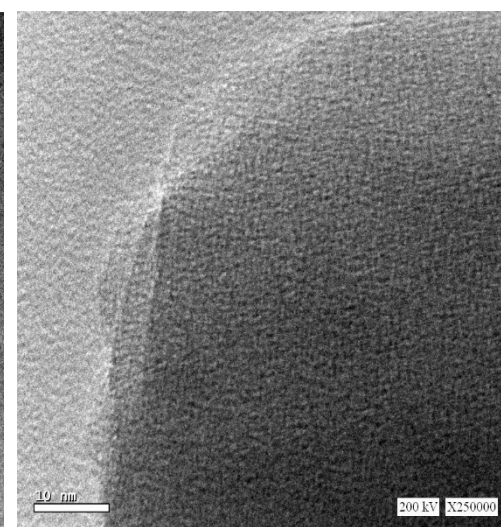
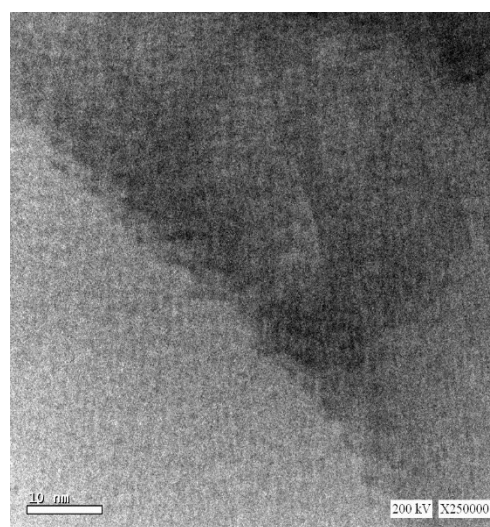
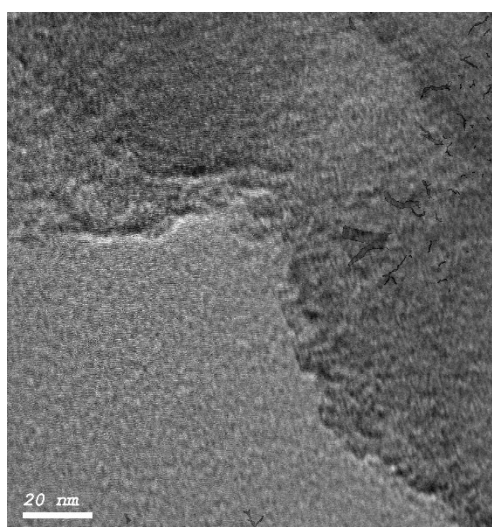
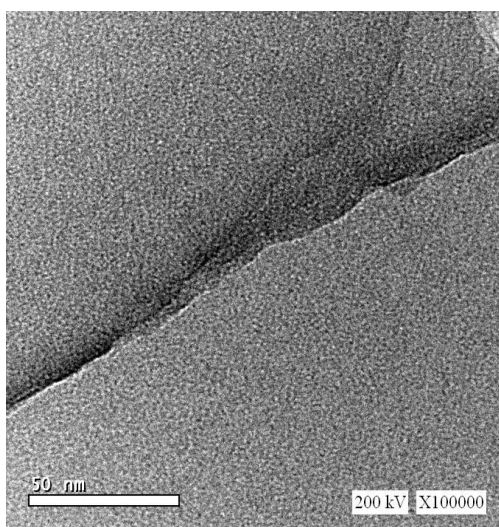
**Fig. S4** Low magnification HR-TEM micrographs of H-NGs270 at various regions within the sample



**Fig. S5 High magnification HR-TEM micrographs of H-NGs270 at various regions within the sample**



(a)



(b)

Fig. S6 HR-TEM micrographs of HTA-NG600 at various regions. (a) low magnification and (b) high magnification